

Halogen Free, High Tg, High Elastic Modulus, Ultra Low CTE material

MCL-E-795G

High Tg Glass Epoxy Material

■ Features

- MCL-E-795G has low CTE value in X, Y directions and can reduce warpage of package significantly.
- MCL-E-795G type (LH) has ultra low CTE value (<1.0ppm/°C)
- Well-suited for center core of build-up construction.

■ Applications

- Semiconductor packages (FC-BGA)
- Center core for build-up construction

■ Standard Specifications

Part Number	Type	Copper foil thickness	Thickness code	Actual thickness and Tolerance
MCL-E-795G	—	12μm(STD,LP)	0.11	0.11±0.02mm
			0.21	0.21±0.02mm
			0.41	0.41±0.04mm
			0.62	0.62±0.06mm
			0.72	0.72±0.06mm
			0.82	0.82±0.08mm
			1.03	1.03±0.10mm
			1.23	1.23±0.12mm
			1.44	1.44±0.14mm
	(LH)		0.11	0.11±0.02mm
			0.21	0.21±0.02mm
			0.42	0.41±0.04mm
			0.63	0.62±0.06mm
			0.73	0.72±0.06mm
			0.84	0.82±0.08mm
			1.05	1.03±0.10mm
			1.26	1.23±0.12mm
			1.47	1.44±0.14mm

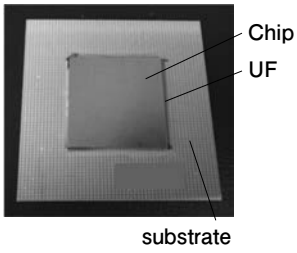
Note1) STD:Standard copper foil, LP:Low profile copper foil.
 Note2) The thickness means that of dielectric layer.

■ Characteristics

(t0.2mm)

Item	Condition *2	Unit	Actual Value		Test Method (IPC-TM-650)
			MCL-E-795G	MCL-E-795G type (LH)	
Tg	TMA	°C	260~290		2.4.24
	DMA		300~360		—
CTE *1	X	°C	3.0~5.0	0.5~1.5	2.4.24
	Y		3.0~5.0	0.5~1.5	
Flexural Modulus (Lengthwise)	A	GPa	37~39	42~44	2.4.4
Decomposition Temperature (5% weight loss)	TGA	°C	430~450	430~450	2.3.40
Solder heat resistance (260°C)	A	sec.	>300	>300	—
T-260	TMA	min.	>60	>60	2.4.24.1
T-288			>60	>60	
Copper Peel strength (12μm)	A	kN/m	0.7~0.9	0.7~0.9	2.4.8

*1) Heating Rate:10°C/min. *2) Refer to last page "Condition Note"



● Warpage of 8 layer TEG

- *Substrate : 3-2-3 construction, BU thickness 20 μ m
- *Package size : 40mm \times 40mm
- *Die size : 20mm \times 20mm
- *Die height : 775 μ m
- *Underfill thickness : 60 μ m
- * L1,4,5,8 : 12 μ m Cu 65%, L2,3,6,7 : No copper, SR thickness:19 μ m

